

L Number	Hits	Search Text	DB	Time stamp
-	66	method and (statistical adj outlier\$1)	USPAT; US-PGPUB	2002/11/01 16:13
-	1	method near2 (statistical adj outlier\$1)	USPAT; US-PGPUB	2002/10/28 20:35
-	3247	((integrate\$1 or circuit\$1) near2 die) and (438/\$.ccls. or 257/\$.ccls. or 324/\$.ccls.)	USPAT; US-PGPUB	2002/10/28 21:34
-	8831	(semiconductor or (integrate\$1 near circuit) or substrate or wafer or die) and averag\$3 and (absolute adj value\$1)	USPAT; US-PGPUB	2002/10/30 23:11
-	42	((integrate\$1 or circuit\$1) near2 die) and (438/\$.ccls. or 257/\$.ccls. or 324/\$.ccls.) and (target and average)	USPAT; US-PGPUB	2002/10/28 21:31
-	5045	((semiconductor or (integrate\$1 near circuit) or substrate or wafer or die) and averag\$3 and (absolute adj value\$1)) and calculat\$3 and difference\$1	USPAT; US-PGPUB	2002/10/28 21:32
-	288	-(semiconductor-or-(integrate\$1 near circuit) or substrate or wafer or die) and averag\$3 and (absolute adj value\$1)) and calculat\$3 and difference\$1) and (438/\$.ccls. or 257/\$.ccls. or 324/\$.ccls.)	USPAT; US-PGPUB	2002/10/28 21:34
-	861	(438/14).CCLS.	USPAT; US-PGPUB	2002/10/28 21:53
-	482	(438/15).CCLS.	USPAT; US-PGPUB	2002/10/28 21:53
-	571	(438/17).CCLS.	USPAT; US-PGPUB	2002/10/28 21:53
-	433	(438/460).CCLS.	USPAT; US-PGPUB	2002/10/28 21:53
-	45	((438/15).CCLS.) and averag\$3	USPAT; US-PGPUB	2002/10/28 21:54
-	109	((438/17).CCLS.) and averag\$3	USPAT; US-PGPUB	2002/10/28 21:54
-	40	((438/460).CCLS.) and averag\$3	USPAT; US-PGPUB	2002/10/28 21:54
-	169	((438/14).CCLS.) and averag\$3	USPAT; US-PGPUB	2002/10/29 20:29
-	1	(US-20020102749-\$).did.	US-PGPUB	2002/10/28 21:56
-	1	(US-20020066859-\$).did.	US-PGPUB	2002/10/28 22:01
-	1	(US-6419846-\$).did.	USPAT	2002/10/28 22:03
-	1	(US-6240329-\$).did.	USPAT	2002/10/28 22:10
-	8202	(semiconductor or (integrate\$1 near circuit) or substrate or wafer or die) and average and (absolute adj value\$1)	USPAT; US-PGPUB	2002/10/30 23:12
-	1408	(semiconductor or (integrate\$1 near circuit) or substrate or wafer or die) and (average same (absolute adj value\$1))	USPAT; US-PGPUB	2002/10/30 23:14
-	2246	quiescent adj current	USPAT; US-PGPUB	2002/11/01 19:01
-	45	(quiescent adj current) and average\$1 and (absolute adj value\$1)	USPAT; US-PGPUB	2002/11/01 16:56
-	922	(quiescent adj current) and (wafer or substrate or chip or die)	USPAT; US-PGPUB	2002/11/01 17:07
-	331	((quiescent adj current) and (wafer or substrate or chip or die)) and variation	USPAT; US-PGPUB	2002/11/01 17:09
-	114	(quiescent adj current) same variation	USPAT; US-PGPUB	2002/11/01 18:28
-	0	iddq and (statistic\$2 near2 outlier\$1)	USPAT; US-PGPUB	2002/11/01 18:29
-	93	statistic\$2 near2 outlier\$1	USPAT; US-PGPUB	2002/11/01 18:29
-	89	((quiescent adj current) or iddq) same averag\$3	USPAT; US-PGPUB	2002/11/01 19:47

-	533	(leakage adj current) same averag\$3	USPAT; US-PGPUB	2002/11/01 19:48
-	197	(leakage adj current) same (absolute adj value\$1)	USPAT; US-PGPUB	2002/11/01 19:48
-	14	((leakage adj current) same averag\$3) and ((leakage adj current) same (absolute adj value\$1))	USPAT; US-PGPUB	2002/11/01 19:50
-	28785	calculat\$3 near2 difference\$1	USPAT; US-PGPUB	2002/11/01 19:51
-	2866	calculat\$3 near2 (absolute adj value\$1)	USPAT; US-PGPUB	2002/11/01 19:51
-	24006	calculat\$3 near2 averag\$3	USPAT; US-PGPUB	2002/11/01 19:51
-	290	(calculat\$3 near2 difference\$1) and (calculat\$3 near2 (absolute adj value\$1)) and (calculat\$3 near2 averag\$3)	USPAT; US-PGPUB	2002/11/01 20:03
-	194	((calculat\$3 near2 difference\$1) and (calculat\$3 near2 (absolute adj value\$1)) and (calculat\$3 near2 averag\$3)) and (device or wafer or substrate or semiconductor)	USPAT; US-PGPUB	2002/11/01 20:08
-	40	((calculat\$3 near2 difference\$1) and (calculat\$3 near2 (absolute adj value\$1)) and (calculat\$3 near2 averag\$3)) and (wafer or substrate or semiconductor)	USPAT; US-PGPUB	2002/11/01 20:08